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**OFFICE OF DIRECTOR
GROUP**

In re Application of: :
Witehira *et al.* :
Application No. 09/622,535 :
Filed: November 22, 2000 :
Fro: Multi-layer Display and a Method for :
Displaying Images on Such a Display :

**DECISION ON PETITION
TO MAKE SPECIAL**

This is a decision on the petition under 37 C.F.R. § 1.102, filed March 1, 2002, to make the above-identified application special under the accelerated examination procedure set forth in M.P.E.P. § 708.02, Item VIII: Accelerated Examination.

A grantable petition to make special under 37 C.F.R. § 1.102 and in accordance with M.P.E.P., Section 708.02, Item VIII, must be accompanied by:

- (a) the required petition fee set forth in 37 C.F.R. § 1.17(h),
- (b) a statement that all claims are directed a single invention or in the event that the United States Patent and Trademark Office determines that all the claims presented are not obviously directed to a single invention, applicant will make an election without traverse as a prerequisite to the grant of special status,
- (c) a statement that a pre-examination search has been made by the inventor, attorney, agent, professional searcher, etc., and a listing of the field of search by class and subclass,
- (d) one copy of each of the references deemed most closely related to the subject matter encompassed by the claims, and
- (e) a detailed description of the submitted references and discussions pointing out how the claimed subject matter is distinguishable over these references.

The petition includes a showing that complies with the above requirements to permit the application to be made special under the accelerated examination procedure.

Accordingly, the petition is **granted**.

The application is being forwarded to the examiner for accelerated examination in accordance with the M.P.E.P. § 708.01.

After allowance, this application will be given priority for printing. See M.P.E.P. § 1309.

Inquiries regarding this decision should be directed to Ed Glick at (703) 308-4858.



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